

STP62NS04Z

N-CHANNEL CLAMPED 12.5mΩ - 62A TO-220 FULLY PROTECTED MESH OVERLAY™ MOSFET

TYPE	V _{DSS}	R _{DS(on)}	I _D	
STP62NS04Z	CLAMPED	<0.015 Ω	62 A	

- TYPICAL $R_{DS}(on) = 0.0125 \Omega$
- 100% AVALANCHE TESTED
- LOW CAPACITANCE AND GATE CHARGE
- 175 °C MAXIMUM JUNCTION TEMPERATURE

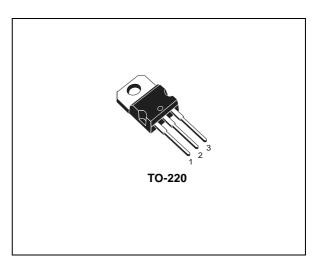
DESCRIPTION

This fully clamped Mosfet is produced by using the latest advanced Company's Mesh Overlay process which is based on a novel strip layout.

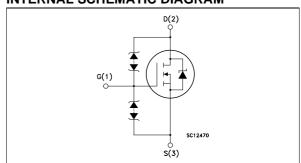
The inherent benefits of the new technology coupled with the extra clamping capabilities make this product particularly suitable for the harshest operation conditions such as those encountered in the automotive environment. Any other application requiring extra ruggedness is also recommended.

APPLICATIONS

- ABS, SOLENOID DRIVERS
- POWER TOOLS



INTERNAL SCHEMATIC DIAGRAM



Ordering Information

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SALES TYPE	MARKING	PACKAGE	PACKAGING
STP62NS047	P62NS04Z	TO-220	TUBF

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source Voltage (V _{GS} = 0)	CLAMPED	V
V_{DG}	Drain-gate Voltage	CLAMPED	V
V_{GS}	Gate- source Voltage	CLAMPED	V
I _D	Drain Current (continuous) at T _C = 25°C	62	Α
I _D	Drain Current (continuous) at T _C = 100°C	37.5	Α
I _{DG}	Drain Gate Current (continuous)	± 50	mA
I _{GS}	Gate SourceCurrent (continuous)	± 50	mA
I _{DM} (●)	Drain Current (pulsed)	248	A
P _{tot}	Total Dissipation at T _C = 25°C	110	W
	Derating Factor	0.74	W/°C
dv/dt (1)	Peak Diode Recovery voltage slope	8	V/ns
E _{AS} (2)	Single Pulse Avalanche Energy	500	mJ
V _{ESD}	ESD (HBM - C = 100pF, R=1.5 kΩ)	8	kV
T _{stg}	Storage Temperature	-55 to 175	°C
T _j	Operating Junction Temperature	-55 to 175	C

^(•) Pulse width limited by safe operating area.

(2) Starting $T_i = 25 \, {}^{\circ}\text{C}$, $I_D = 20 \, A$, $V_{DD} = 20 \, V$

March 2004 1/8

⁽¹⁾ $I_{SD} \le 40A$, $di/dt \le 100A/\mu s$, $V_{DD} \le V_{(BR)DSS}$, $T_j \le T_{JMAX}$

THERMAL DATA

Rthj-case Rthj-amb T _I Thermal Resistance Junction-case Thermal Resistance Junction-ambient Maximum Lead Temperature For Soldering (for 10 sec., 1.6mm from case)	Max	1.36	°C/W
	Max	62.5	°C/W
	Purpose	300	°C

ELECTRICAL CHARACTERISTICS (T_{case} = 25 °C unless otherwise specified)

OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Clamped Voltage	$I_D = 1 \text{ mA}, V_{GS} = 0$	33			V
I _{DSS}	Zero Gate Voltage Drain Current (V _{GS} = 0)	V _{DS} = 16 V			10	μA
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	V _{GS} = ± 10 V			10	μA
V _{GSS}	Gate-Source Breakdown Voltage	I _{GS} = 100 μA	18			V

ON (*)

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$	$I_D = 250 \mu A$	2		4	V
R _{DS(on)}	Static Drain-source On Resistance	V _{GS} = 10 V	I _D = 30 A		12.5	15	mΩ

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
gfs (*)	Forward Transconductance	V _{DS} = 15 V I _D =30A		20		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25V$, $f = 1$ MHz, $V_{GS} = 0$		1330 420 135		pF pF pF

ELECTRICAL CHARACTERISTICS (continued)

SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
^t d(on) t _r	Turn-on Delay Time Rise Time	$\begin{split} V_{DD} &= 20 \text{ V} & I_D = 20 \text{ A} \\ R_G &= 4.7 \ \Omega & V_{GS} = 10 \text{ V} \\ \text{(Resistive Load, Figure 3)} \end{split}$		13 104		ns ns
Q _g Q _{gs} Q _{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V _{DD} = 20 V I _D = 40 A V _{GS} = 10V		34 10 11.5	47	nC nC nC

SWITCHING OFF

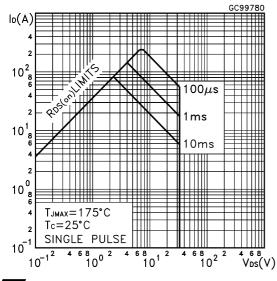
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(off)}	Turn-off Delay Time Fall Time	$\begin{tabular}{ll} $V_{DD}=20$ & $I_{D}=20$ A\\ $R_{G}=4.7$ & $V_{GS}=10$ V\\ (Resistive Load, Figure 3) \end{tabular}$		41 42		ns ns
t _{r(Voff)} t _f t _c	Off-voltage Rise Time Fall Time Cross-over Time	$ \begin{array}{cccccccccccccccccccccccccccccccccccc$		30 54 90		ns ns ns

SOURCE DRAIN DIODE

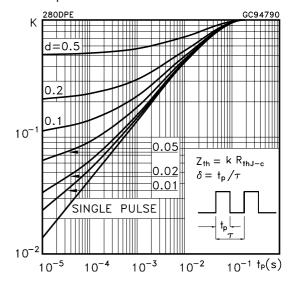
Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} (•)	Source-drain Current Source-drain Current (pulsed)					62 248	A A
V _{SD} (*)	Forward On Voltage	I _{SD} = 62 A	$V_{GS} = 0$			1.5	V
t _{rr} Q _{rr} I _{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	I _{SD} = 40 A V _{DD} = 20 V (see test circuit	di/dt = $100A/\mu s$ $T_j = 150^{\circ}C$ t, Figure 5)		45 65 2.9		ns nC A

^(*)Pulsed: Pulse duration = 300 µs, duty cycle 1.5 %.
(•)Pulse width limited by safe operating area.

Safe Operating Area

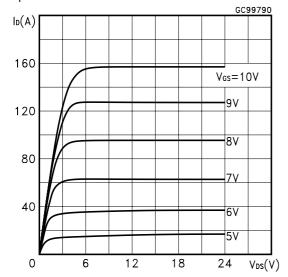


Thermal Impedance

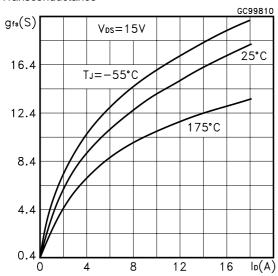


477

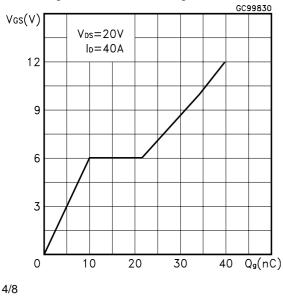
Output Characteristics



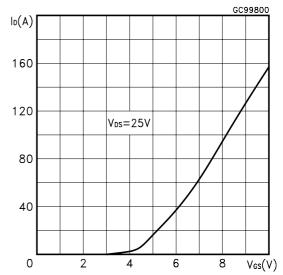
Transconductance



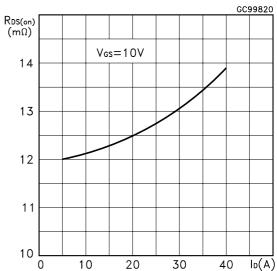
Gate Charge vs Gate-source Voltage



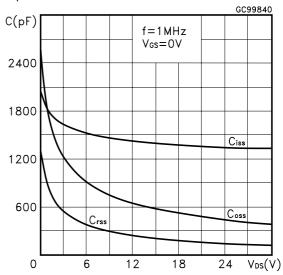
Transfer Characteristics



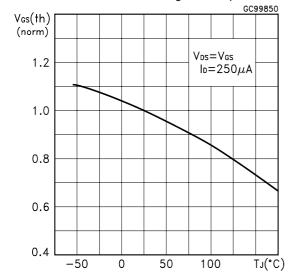
Static Drain-source On Resistance



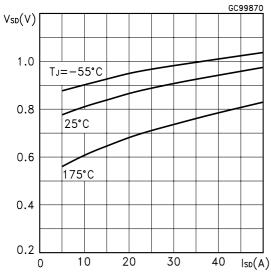
Capacitance Variations



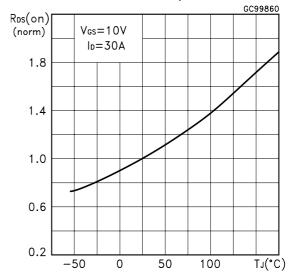
Normalized Gate Threshold Voltage vs Temperature



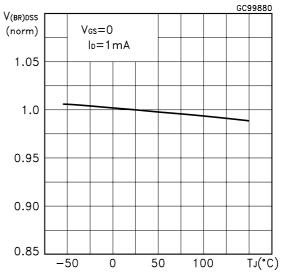
Source-drain Diode Forward Characteristics



Normalized on Resistance vs Temperature



Normalized Breakdown Voltage Temperature.



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Fig. 1: Unclamped Inductive Load Test Circuit

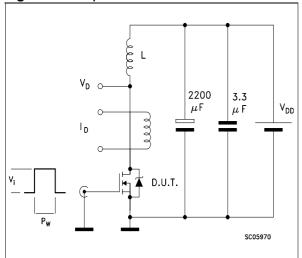


Fig. 3: Switching Times Test Circuits For Resistive Load

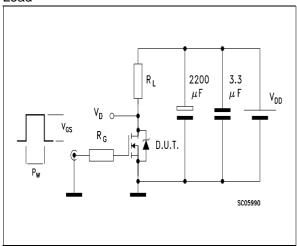


Fig. 5: Test Circuit For Inductive Load Switching And Diode Recovery Times

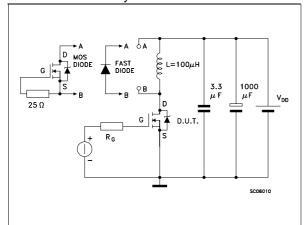


Fig. 2: Unclamped Inductive Waveform

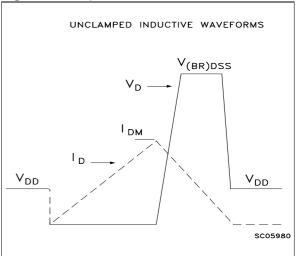
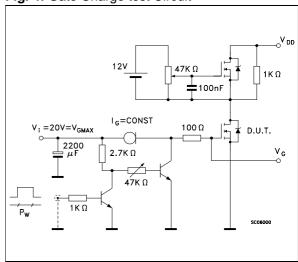
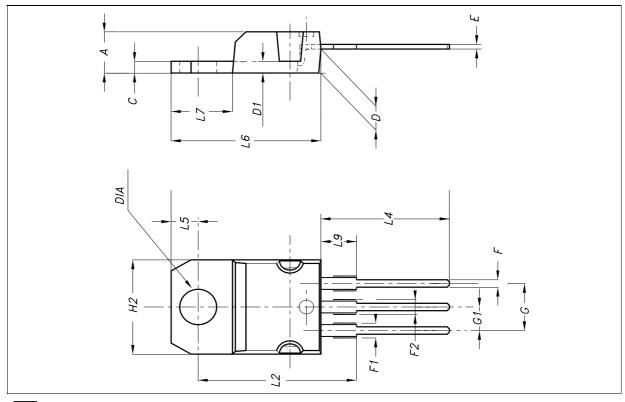


Fig. 4: Gate Charge test Circuit



TO-220 MECHANICAL DATA

DIM		mm.			inch.	
DIM.	MIN.	TYP.	MAX.	MIN.	TYP.	TYP.
Α	4.4		4.6	0.173		0.181
С	1.23		1.32	0.048		0.051
D	2.40		2.72	0.094		0.107
D1		1.27			0.050	
E	0.49		0.70	0.019		0.027
F	0.61		0.88	0.024		0.034
F1	1.14		1.70	0.044		0.067
F2	1.14		1.70	0.044		0.067
G	4.95		5.15	0.194		0.203
G1	2.40		2.70	0.094		0.106
H2	10		10.40	0.393		0.409
L2	16.10	16.40	16.73	0.633	0.645	0.658
L4	13		14	0.511		0.551
L5	2.65		2.95	0.104		0.116
L6	15.25		15.75	0.600		0.620
L7	6.20		6.60	0.244		0.260
L9	3.50		3.93	0.137		0.154
DIA	3.75		3.85	0.147		0.151



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